



X-RAY DIFFRACTOMETER (XRD)

MANUFACTURER : Philips

MODEL : X'Pert

Samples

- Types: all crystalline materials (metals, ceramics, inorganic materials, composites, etc.) as bulk or powder materials

Analysis

- Identification of phases and components
- Semi-quantitative or quantitative (with standards)
- Applications: measurement of mechanical stress, phase identification, low angle measurement

Applications

- Measurement of mechanical stress
- Phase identification
- Low angle measurement

Characteristics

- Two detectors: powder method (Bragg-Breantano) and low angle method
- Interchangeable X-ray sources (Cu or Co)